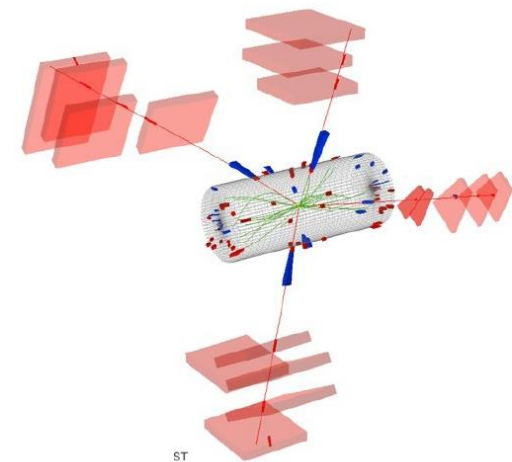


RPCs rate capability (let us calculate...)



M. Abbrescia

Let us start from...

... one of Santonico's presentations:

- In the static limit the voltage applied to the chamber V_a is entirely transferred to the gas but for a working current i part of this voltage is needed to drive the current in the electrodes

$$V_{gas} = V_a - Ri = V_a - V_{el}$$

- The voltage transferred to the electrodes can be written as

$$V_{el} = \rho t r_u \langle Q \rangle$$

ρ is the bulk resistivity of the electrode material; t is the total thickness of both electrodes; $\langle Q \rangle$ is the average charge delivered in the gas for each count and r_u is the counting rate per unit surface

→ A high rate capability requires to keep V_{el} at a negligible value wrt V_{gas} even under heavy irradiation

What we learn from that formula

- Gap thickness seems not to play any role
- Electrode resistivity does influence rate capability
- Electrode thickness does influence rate capability

It is not clear how much a reduction on V_{drop} has on the rate capability:

✓ Anyhow bakelite thickness can account for a 25-50%(? Ex. from 2 → 1.5-1 mm) reduction on V_{drop}

✓ Bakelite resistivity can account a 10 (or more) factor on V_{drop}

Electrode thickness seems to play a second order role.

About gap thickness:

... let us use something older and more elaborate

$$q_{\text{ind}} = \frac{q_e}{ng} \Delta V_w \sum_{j=1}^{N_{\text{el}}} n_0^j M_j [e^{n(\phi - x_0^j)} - 1].$$

Q

The trick is to increase q_{ind} keeping Q constant
 ng stays constant!

$$\Delta V_w = \frac{\epsilon_r g}{n_g \epsilon_r g + (n_g + 1)d}$$

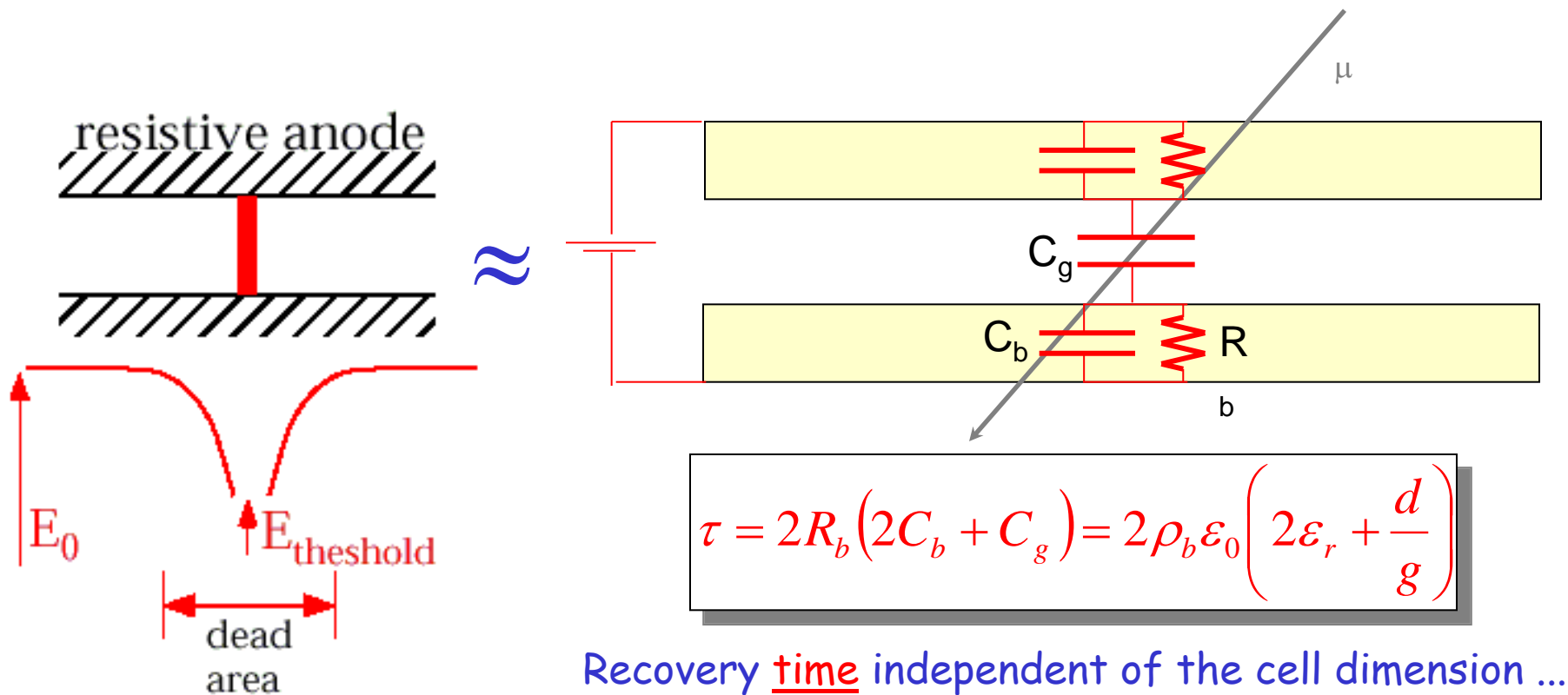
Here g is the gap thickness

- Decreasing the gap thickness alone reduces the induced charge (keeping Q constant)
- Worsen the rate capability

About gap thickness:

- The point is that if you reduce the gap thickness only the shielding electrostatic effect of the bakelite plates increases in proportion
 - The voltage drop related to the weighting field should be as high as possible
 - If you reduce the electrode thickness at the same time, the two effects cancel out, but you do not gain anything in rate capability
-
- ✓ A lot of experimental data showing that wider gaps (9 mm) show a much higher rate capability
 - ✓ It would be strange that the 2 mm gap is the minimum

Let us drop the static model



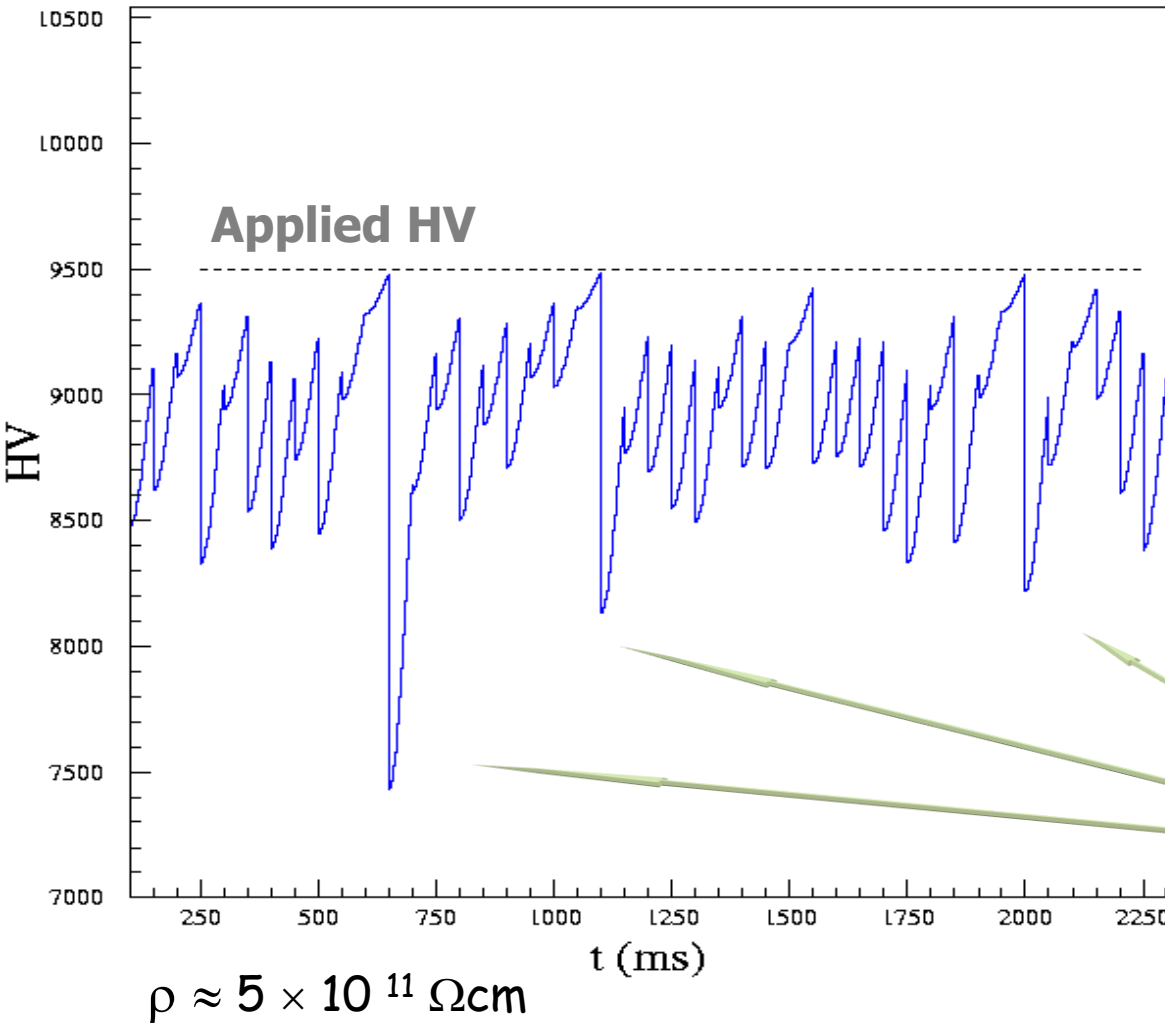
$$\tau = 2R_b(2C_b + C_g) = 2\rho_b \epsilon_0 \left(2\epsilon_r + \frac{d}{g} \right)$$

Recovery time independent of the cell dimension ...

A few numbers:

- typical avalanche radius: 100 μm
- typical avalanche charge: 1 pC
- typical external charge contained in 100 μm : 10 pC

What REALLY happens...



$$i_{ind}(t) = -\mathbf{v}_d \cdot \mathbf{E}_w q_e e^{nv_d t} \sum_{j=1}^{n_{cl}} n_0^j M_j$$

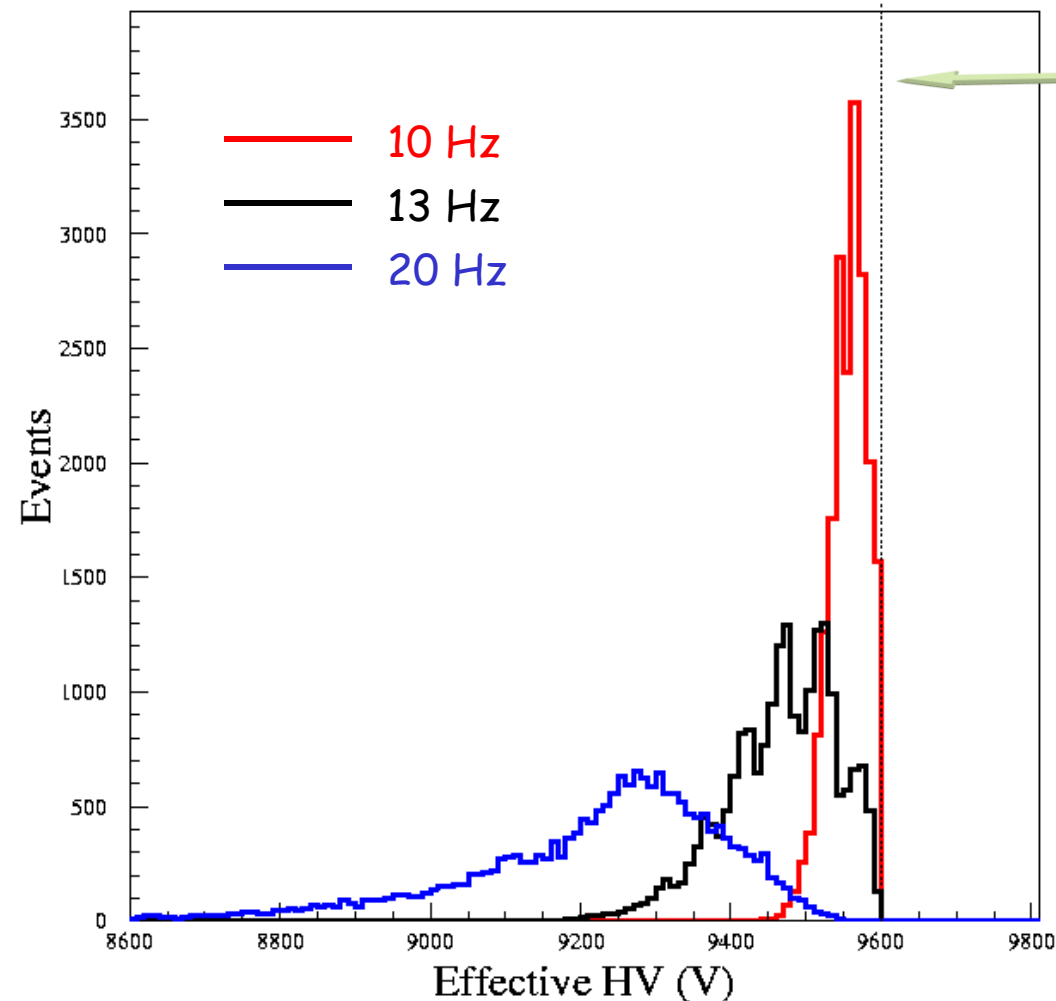
$$\left\{ \begin{array}{l} HV(t) = HV_{ext} \left(1 - e^{-t/\tau} \right) \\ \tau = 1500 \text{ ms} \end{array} \right.$$

There is a sort of feedback ...

High HV "at start"

Big pulses

Some of the differences



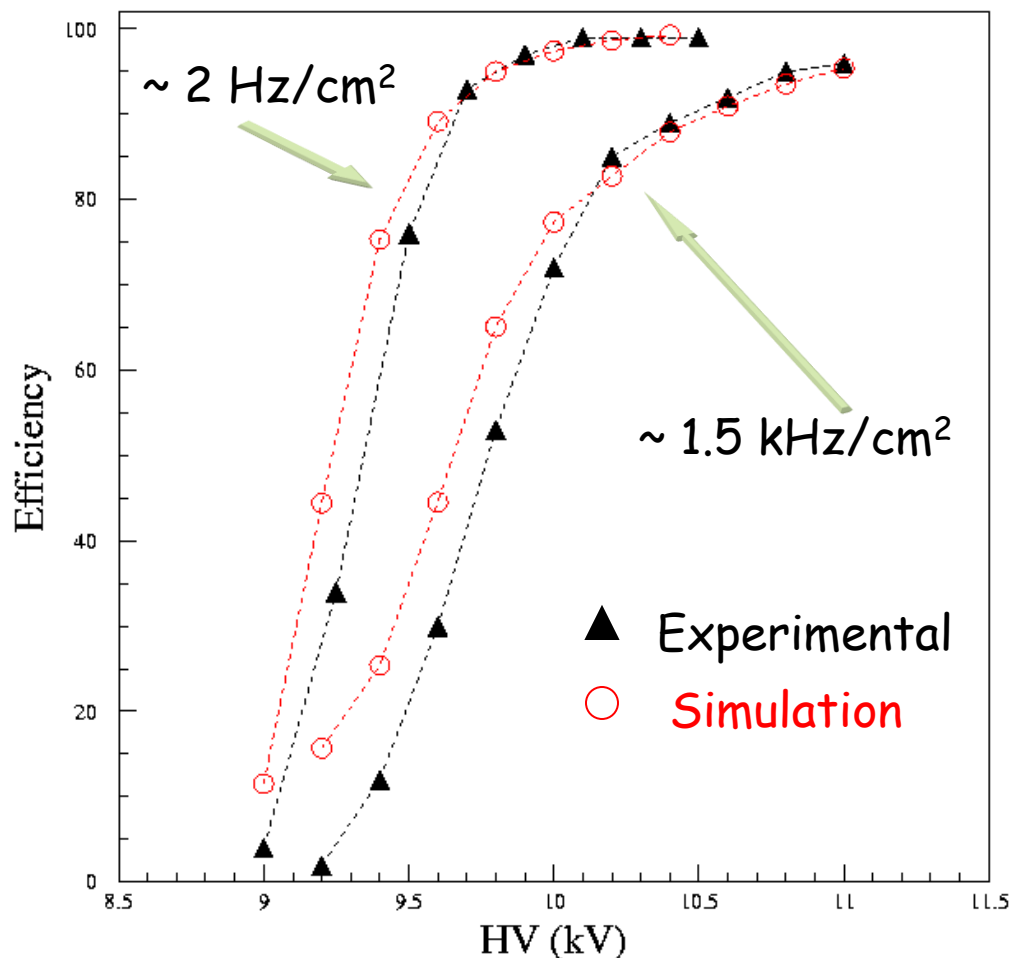
The **effective HV** diminishes and its distribution is broader.

(...until HV_{eff} is too low)

Two consequences:

- **lower HV** at high rate
- **greater HV variations** at high rate

Some comparison with data



Very good agreement

$$\varepsilon = 1 - e^{-\lambda \left[g - \frac{1}{\eta} \ln \left(\frac{q_{thr}}{A} + 1 \right) \right]}$$

$$A = \frac{q_e \Delta V_w M n_0}{\eta g}$$

Data from G. Aielli et al., NIM A 478(2002) 271-276

(Some) Conclusions

- The static model used in the discussions (presentations!) is a really rough approximation of what is happening
 - Like putting a straight line where a complex phenomenon is happening
- Moreover it is wrong! You are assuming a pure resistive behaviour when the capacitive effects are predominant
 - Leads to not correct results
- Anyhow dependance on electrode thickness seems to be a second order effect
- Reducing the gap thickness alone has a negative effect on rate capability

More calculations are welcome